Machine Learning Algorithms for Cybersecurity in IoT Networks

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Message from the Guest Editors

This Special Issue will focus on the application of machine learning algorithms for cybersecurity in IoT networks. We will explore the latest research and developments in this rapidly evolving field. Some of the topics that will be covered include:

- Machine learning-based intrusion detection systems for IoT networks;
- Deep learning techniques for malware detection in IoT networks;
- Use of artificial intelligence for anomaly detection in IoT networks;
- Machine learning-based approaches for secure communication in IoT networks;
- Detection and prevention of DDoS attacks using machine learning in IoT networks;
- Machine learning techniques for risk assessment in IoT networks;
- Secure data analytics in IoT networks using machine learning algorithms;
- Use of machine learning algorithms for IoT network security monitoring;
- Deep learning-based approaches for detecting zero-day attacks in IoT networks;
- Machine learning-based techniques for secure authentication in IoT networks.

Special Issue

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Message from the Editor-in-Chief

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